Search Notes

 Application/Control No.	Applicant(s)/Patent under Reexamination	
10/614,056	ANDO, TAKESHI	
Examiner	Art Unit	
Chuck Huynh	2617	

SEARCHED						
	SEARCHED					
Class	Subclass	Date	Examiner			
Updated	Search	6/4/2007	At At			
455	432.1	6/4/2007	At			
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Class/Subclass	6/4/2007	At		
Combined text search	6/4/2007	4		
Reviewed Applied Art	6/4/2007	4		